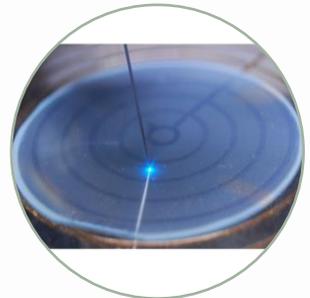
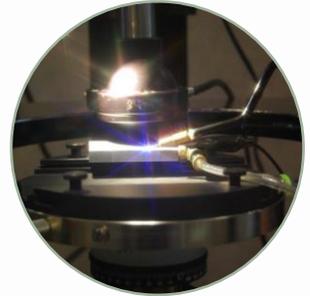
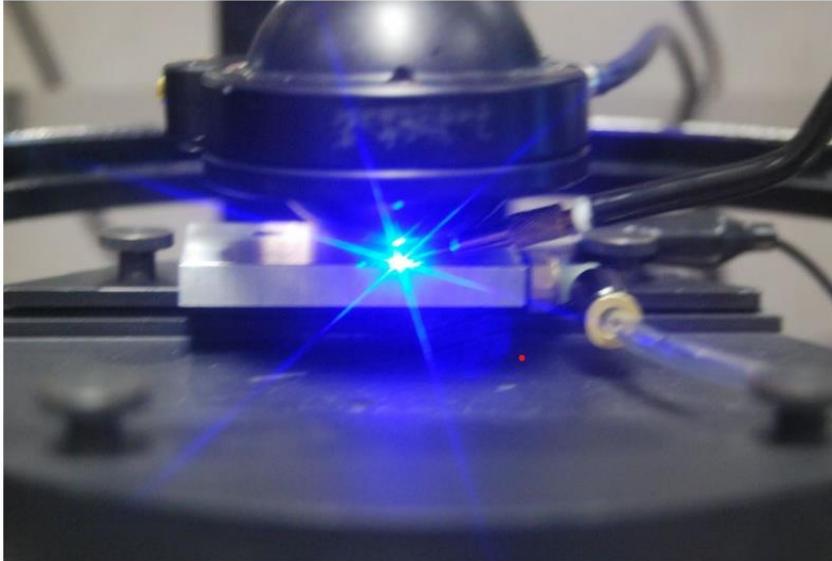




SEMIPROBE®

Test • Inspect • Innovate

SUCCESSFUL APPLICATION: OPTOELECTRONICS - 0616



Specific Requirements:

The customer wanted a semi-automatic probe system to test light emitting diodes (LEDs) in a few different modes - wafer form, wafers sawn and stretched on frames or rings, as partial wafers and as individual die. The device would be biased with a DC manipulator and the light output would be captured by an integrating sphere. The integrating sphere needed to be moved in and out of position on a repeatable basis when required.

SemiProbe Solution:

- SA-6 Semi-automatic 150 mm probe system:
 - 150 mm programmable X, Y, Z and theta stage
 - PILOT Software Suite – Navigator, Wafer Map and Autoalign
 - Vibration Isolation table
- 150 mm wafer chuck and customized holders for frames, rings and die
- Ability to test whole wafers, partial wafers, individual die and wafers sawn and stretched on rings or frames
- Integrating sphere mounted on a manually moved retractable stage
- Manual manipulator with coaxial probe arm and DC probe tip